Search Notes

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10/566,986 Examiner

Jinhee J. Lee

Applicant(s)/Patent under Reexamination

TERADA, TOMOYASU Art Unit

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SEARCHED				
Class	Subclass	Date	Examiner	
174	72a	9/2/2006	LEE	
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174	as above	2/20/2007	LEE	
174	as above	8/1/2007	. LEE	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
174	as above	9/2/2006	LEE
174	as above	8/1/2007	LEE

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
See text search attached	9/2/2006	LEE
see east search attached	8/1/2007	LEE
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